

## ABSTRACT OF THE DISCLOSURE

An object of the present invention is to provide a charged particle beam apparatus and an alignment method of the charged particle beam apparatus, which make it possible to align an optical axis of a charged particle beam easily even when a state of the charged particle beam changes. The present invention comprises calculation means for calculating a deflection amount of an alignment deflector which performs an axis alignment for an objective lens, a plurality of calculation methods for calculating the deflection amount is memorized in the calculation means, and a selection means for selecting at least one of the calculation methods is provided.

1. A charged particle beam apparatus, comprising:  
 a deflector for deflecting a charged particle beam;  
 a calculation means for calculating a deflection amount of the deflector;  
 a selection means for selecting at least one of a plurality of calculation methods for calculating the deflection amount;  
 a memory means for storing the plurality of calculation methods;  
 a control means for controlling the deflector and the calculation means;  
 a display means for displaying a deflection amount of the deflector;  
 a selection means for selecting at least one of a plurality of calculation methods for calculating the deflection amount;  
 a memory means for storing the plurality of calculation methods;  
 a control means for controlling the deflector and the calculation means;  
 a display means for displaying a deflection amount of the deflector;